

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Edgar Voelkl
Serial No.: 10/661,873
Date Filed: September 12, 2003
Group Art Unit: 2625
Examiner: Couso, Yon Jung
Title: **SYSTEM AND METHOD FOR DETECTING
DIFFERENCES BETWEEN COMPLEX IMAGES**

MAIL STOP - AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this Information Disclosure Statement is being deposited with the United States Postal Service as Express Mail No. EV351287685US addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on February 2, 2005.

Adesewa Faleti

Dear Sir:

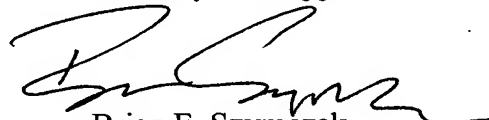
INFORMATION DISCLOSURE STATEMENT

Applicant respectfully requests, pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, that the references listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. Copies of the references are enclosed for the Examiner's convenience. Furthermore, pursuant to 37 C.F.R. §§1.97(g) and (h), no representation is made that these references are material to the patentability of the present application.

Applicant believes no fees are due, however, the Commissioner is hereby authorized to charge any fees to Deposit Account No. 50-2148 of Baker Botts L.L.P. in order to effectuate this filing.

Respectfully submitted,

BAKER BOTTS L.L.P.
Attorneys for Applicant




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Date: 2/02/05

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PTO-1449 		Patent No. 10/661,873 Docket Number 068062.0167		Applicant(s) Edgar Voelkl Group Art Unit 2625 Filing Date September 12, 2003			
U.S. PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	A.						
	B.						
	C.						
	D.						
	E.						
	F.						
	G.						
	H.						
	I.						
	J.						
	K.						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	L.						
	M.						
	N.						
NON-PATENT DOCUMENTS							
		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
	O.	International Search Report for PCT/US03/28877, 8 pages					Mailed 12/28/04
	P.	Lindlein, et al., <i>Axicon-Type Test Interferometer for Cylindrical Surfaces: Systematic Error Assessment</i> , Applied Optics, Vol. 36, No. 13, pp. 2791-2795					5/1/97
	Q.	Q. Fu, et al., <i>Correction of Aberrations of an Electron Microscope by Means of Electron Holography</i> , The American Physical Society, Vol. 67, No. 17, pp. 2319-2322					10/21/91
	R.						
	S.						
EXAMINER				DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.							